Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/543,171	RENAUDIN ET AL.	
Examiner	Art Unit	
Hae M. Hyeon	2839	

	SEARCHED				
Class	Subclass	Date	Examiner		
439	807	10/06	hmh		
439	799				
439	797				
439	858				
439	1				
439	801				
439	810				
439	213				
439	784				
439	781				
439	805				
439	33				
65	492				
65	496	V			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
		-		

(INCLUDING SEARCH S	DATE	EXMR
	1	_
•		